

Rev. 04/03

Docket No. ELM-2 Div. 6

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicant : Glenn J. Leedy

Application No.: 10/614,067 Confirmation No.: 8117

Filed : July 3, 2003

For : THREE DIMENSIONAL STRUCTURE
INTEGRATED CIRCUIT

Group Art Unit : 2812

Examiner : Not yet assigned

New York, New York
August 11, 2004

Hon. Commissioner for Patents
P.O. Box 1450
Alexandria, Virginia 22313-1450

TRANSMITTAL LETTER FOR
INFORMATION DISCLOSURE STATEMENT

Sir:

Transmitted herewith is an Information
Disclosure Statement in the above-identified application.
This Statement is submitted:

[] within three months of the application filing date;

more than three months from the application filing date but before the mailing date of the first Office Action on the merits.

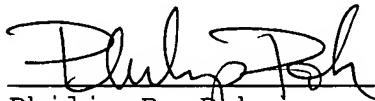
In accordance with 37 C.F.R. § 1.97, submission of this Statement requires no fee. However, if for any reason a fee is due, the Director is hereby authorized to charge payment of any fees required in connection with this



Information Disclosure Statement to Deposit Account

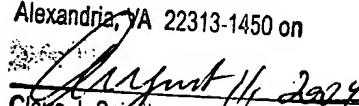
No. 06-1075. A duplicate copy of this letter is transmitted herewith.

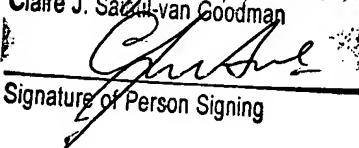
Respectfully submitted,



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Alexandria, VA 22313-1450 on


Claire J. Saad-van Goodman


Christine
Signature of Person Signing



ELM-2 Div. 6

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

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Alexandrian, Virginia 22313-1450

INFORMATION DISCLOSURE STATEMENT

Sir:

In accordance with 37 C.F.R. §§ 1.56 and 1.97,
applicant wishes to call the attention of the Examiner to
the following documents:

U.S. Patents

| | | |
|---------------------|------------|----------|
| Fujii et al. | Re. 34,893 | 04/04/95 |
| Foster | 2,915,722 | 12/01/59 |
| Farrand | 3,202,948 | 08/24/65 |
| Lesk | 3,559,282 | 02/02/71 |
| Burkhardt | 3,560,364 | 02/02/71 |
| Emmasingel | 3,602,982 | 09/07/71 |
| Medicus | 3,615,901 | 10/26/71 |
| Napoli et al. | 3,716,429 | 02/13/73 |
| Krishna et al. | 3,777,227 | 12/14/73 |
| Kuipers | 3,868,565 | 02/25/75 |
| Yerman | 3,922,705 | 11/25/75 |
| Wanlass | 3,997,381 | 12/14/76 |
| Stein | 4,070,230 | 01/24/78 |
| Greenwood et al. | 4,131,985 | 01/02/79 |
| Hauser, Jr., et al. | 4,142,004 | 02/27/79 |

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| Hoeberechts | 4,251,909 | 02/24/81 |
| Kubacki | 4,262,631 | 04/21/81 |
| Shioya et al. | 4,394,401 | 07/19/83 |
| Trenkler et al. | 4,401,986 | 08/30/83 |
| Thomas et al. | 4,416,054 | 11/22/83 |
| Takagi et al. | 4,539,068 | 09/03/85 |
| Reid et al. | 4,585,991 | 04/29/86 |
| Yasumoto et al. | 4,612,083 | 09/16/86 |
| Belanger et al. | 4,617,160 | 10/14/86 |
| Shimizu et al. | 4,618,397 | 10/21/86 |
| Schmitz | 4,618,763 | 10/21/86 |
| Christensen | 4,663,559 | 05/05/87 |
| Burns et al. | 4,684,436 | 08/04/87 |
| Hatada | 4,693,770 | 09/15/87 |
| Maeda et al. | 4,702,336 | 10/27/87 |
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| Go | 4,706,166 | 11/10/87 |
| Stevenson | 4,721,938 | 01/26/88 |
| Reid | 4,761,681 | 08/02/88 |
| Holmen et al. | 4,784,721 | 11/15/88 |
| Freeman | 4,810,673 | 03/07/89 |
| Mattox et al. | 4,825,277 | 04/25/89 |
| Tam et al. | 4,857,481 | 08/15/89 |
| Leedy | 4,924,589 | 05/15/90 |
| Borel et al. | 4,940,916 | 07/10/90 |
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| Rokos | 4,954,865 | 09/04/90 |
| Shinomiya | 4,957,882 | 09/18/90 |
| Young et al. | 4,965,415 | 10/23/90 |
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| Allen et al. | 5,010,024 | 04/23/91 |
| Leedy | 5,020,219 | 06/04/91 |
| Leedy | 5,034,685 | 07/23/91 |
| Greenwald et al. | 5,070,026 | 12/03/91 |
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| Machado et al. | 5,098,865 | 03/24/92 |
| Leedy | 5,103,557 | 04/14/92 |
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| Chan et al. | 5,116,777 | 05/26/92 |
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| Henager, Jr., et al. | 5,156,909 | 10/20/92 |
| Zimmerman | 5,203,731 | 04/20/93 |
| Leedy | 5,225,771 | 07/06/93 |
| Bower et al. | 5,236,118 | 08/17/93 |
| Bureau et al. | 5,262,351 | 11/16/93 |
| Bertin et al. | 5,270,261 | 12/14/93 |
| Sanders | 5,273,940 | 12/28/93 |
| Tuckerman | 5,274,270 | 12/28/93 |
| Chebi et al. | 5,279,865 | 01/18/94 |
| Nakanishi et al. | 5,284,796 | 02/08/94 |
| Leedy | 5,323,035 | 06/21/94 |
| Wojnarowski | 5,324,687 | 06/28/94 |
| Leedy | 5,354,695 | 10/11/94 |
| MacDonald | 5,363,021 | 11/08/94 |
| Goossen | 5,385,632 | 01/31/95 |
| Nelson et al. | 5,385,909 | 10/25/94 |
| Shimoji | 5,420,458 | 05/30/95 |
| Miyake | 5,424,920 | 06/13/95 |
| Finnila | 5,426,072 | 06/20/95 |
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| Naruse | 5,476,813 | 12/19/95 |
| Gates | 5,489,554 | 02/06/96 |
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| Sotokawa et al. | 5,868,949 | 02/09/99 |
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| Sweatt et al. | 5,870,176 | 02/09/99 |
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| JAPAN | JP 02-082564 | 03/1990 |
| JAPAN | JP 04-083371 | 03/1992 |
| JAPAN | JP 04-107964 | 04/1992 |
| JAPAN | JP 402027600A | 01/1990 |

Other Documents

"IC Tower Patent: Simple Technology Receives Patent on the IC Tower, a Stacked Memory Technology,"
<http://www.simpletech.com/whatsnew/memory/@60824.htm> (1998).

Alloert, K., et al., "A Comparison Between Silicon Nitride Films Made by PCVD of N₂-SiH₄/Ar and N₂-SiH₄/He," Journal of the Electrochemical Society, Vol. 132, No. 7, pp. 1763-1766, (July 1985).

Hendricks, et al., "Polyquinoline Coatings and Films: Improved Organic Dielectrics for IC's and MCM's," Eleventh IEEE/CHMT International Electronics Manufacturing Technology Symposium," pp. 361-265 (1991).

Knolle, W.R., et al., "Characterization of Oxygen-Doped, Plasma-Deposited Silicon Nitride," Journal of the Electrochemical Society, Vol. 135, No. 5, pp. 1211-1217, (May 1988).

Nguyen, S.V., "Plasma Assisted Chemical Vapor Deposited Thin Films for Microelectronic Applications, J. Vac. Sci. Technol. Vol. B4, No. 5, pp. 1159-1167, (Sep/Oct. 1986).

Olmer, et al., "Intermetal Dielectric Deposition by Plasma Enhanced Chemical Vapor Deposition," Fifth IEEE/CHMT International Electronic Manufacturing Technology Symposium - Design-to-Manufacturing Transfer Cycle," pp. 98-99 (1988).

Runyan, W.R., "Deposition of Inorganic Thin Films," Semiconductor Integrated Circuit Processing Technology, p. 142 (1990).

Sze, S.M., "Surface Micromachining," Semiconductor Sensors, pp. 58-63 (1994).

Vossen, John L., "Plasma-Enhanced Chemical Vapor Deposition," Thin Film Processes II, pp. 536-541 (1991).

Wolf, Stanley, "Basic of Thin Films," *Silicon Processing for the VLSI Era*, pp. 115, 192-193 and 199 (1986).

Copies of the aforementioned documents are listed on the accompanying Form PTO-1449 (submitted in duplicate).

It is respectfully requested that these documents be:

(1) fully considered by the Patent and Trademark Office during the examination of this application; and (2) printed on any patent which may issue on this application.

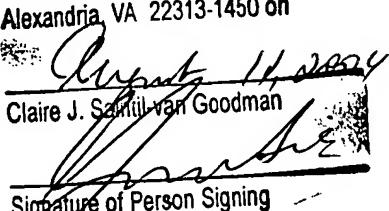
Applicant requests that a copy of Form PTO-1449, as considered and initialized by the Examiner, be returned with the next communication.

Consideration of the foregoing in relation to this patent application is respectfully requested.

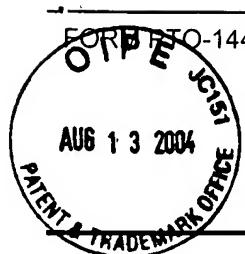
Respectfully submitted,


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Tel.: (212) 596-9000

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August 14, 2024


Claire J. Samoil van Goodman


Signature of Person Signing



U.S. DEPARTMENT OF COMMERCE
PATENT AND TRADEMARK OFFICE

INFORMATION DISCLOSURE
STATEMENT BY APPLICANT

ATTY. DOCKET NO.
ELM-2 Div. 6

APPLICATION NO.
10/614,067

APPLICANT
Glenn J. Leedy

CONFIRMATION NO.
8117

FILING DATE
July 3, 2003

GROUP
2812

U.S. PATENT DOCUMENTS

| EXAMINE R INITIAL | DOCUMENT NUMBER | DATE | NAME | CLASS | SUBCLASS | FILING DATE IF APPROPRIATE |
|-------------------|-----------------|----------|--------------------|-------|----------|----------------------------|
| | Re. 34,893 | 04/04/95 | Fujii et al. | 257 | 419 | |
| | 2,915,722 | 12/01/59 | Foster | 336 | 115 | |
| | 3,202,948 | 08/24/65 | Farrand | 336 | 115 | |
| | 3,559,282 | 02/02/71 | Lesk | 438 | 113 | |
| | 3,560,364 | 02/02/71 | Burkhardt | 324 | 207.12 | |
| | 3,602,982 | 09/07/71 | Emmasingel | 29 | 577 | |
| | 3,615,901 | 10/26/71 | Medicus | 148 | 11.5 R | |
| | 3,716,429 | 02/13/73 | Napoli et al. | 156 | 17 | |
| | 3,777,227 | 12/14/73 | Krishna et al. | 257 | 578 | |
| | 3,868,565 | 02/25/75 | Kuipers | 324 | 207.26 | |
| | 3,922,705 | 11/25/75 | Yerman | 357 | 26 | |
| | 3,997,381 | 12/14/76 | Wanlass | 156 | 3 | |
| | 4,070,230 | 01/24/78 | Stein | 156 | 657 | |
| | 4,131,985 | 01/02/79 | Greenwood et al. | 29 | 580 | |
| | 4,142,004 | 02/27/79 | Hauser, Jr. et al. | 438 | 792 | |
| | 4,251,909 | 02/24/81 | Hoeberechts | 29 | 580 | |
| | 4,262,631 | 04/21/81 | Kubacki | 118 | 723MP | |
| | 4,394,401 | 07/19/83 | Shioya et al. | 427 | 574 | |
| | 4,401,986 | 08/30/83 | Trenkler et al. | 340 | 870.32 | |
| | 4,416,054 | 11/22/83 | Thomas et al. | 29 | 572 | |
| | 4,539,068 | 09/03/85 | Takagi et al. | 156 | 614 | |
| | 4,585,991 | 04/29/86 | Reid et al. | 324 | 158 P | |
| | 4,612,083 | 09/16/86 | Yasumoto et al. | 156 | 633 | |
| | 4,617,160 | 10/14/86 | Belanger et al. | 264 | 40.1 | |
| | 4,618,397 | 10/21/86 | Shimizu et al. | 156 | 628 | |
| | 4,618,763 | 10/21/86 | Schmitz | 250 | 211R | |
| | 4,663,559 | 05/05/87 | Christensen | 313 | 336 | |
| | 4,684,436 | 08/04/87 | Burns et al. | 216 | 65 | |
| | 4,693,770 | 09/15/87 | Hatada | 156 | 151 | |

EXAMINER

DATE CONSIDERED

EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not conformance and not considered. Include copy of this form with next communication to applicant.

| | | | | | |
|--|--|--|-----------------------------|----------------------------------|-------------------------------|
| FORM PTO-1449 | U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE | | | ATTY. DOCKET NO. ELM-2 Div. 6 | APPLICATION NO. 10/614,067 |
| INFORMATION DISCLOSURE STATEMENT BY APPLICANT | | | APPLICANT Glenn J. Leedy | CONFIRMATION NO. 8117 | |
| | | | FILING DATE July 3, 2003 | GROUP 2812 | |
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|----------------|----------|------------------|-----|--------|--|
| 4,702,336 | 10/27/87 | Maeda et al. | 180 | 197 | |
| 4,702,936 | 10/27/87 | Seibert et al. | 427 | 583 | |
| 4,706,166 | 11/10/87 | Go | 361 | 403 | |
| 4,721,938 | 01/26/88 | Stevenson | 338 | 4 | |
| 4,761,681 | 08/02/88 | Reid | 357 | 68 | |
| 4,784,721 | 11/15/88 | Holmen et al. | 156 | 647 | |
| 4,810,673 | 03/07/89 | Freeman | 438 | 386 | |
| 4,825,277 | 04/25/89 | Mattox et al. | 257 | 639 | |
| 4,857,481 | 08/15/89 | Tam et al. | 438 | 619 | |
| 4,924,589 | 05/15/90 | Leedy | 438 | 6 | |
| 4,940,916 | 07/10/90 | Borel et al. | 313 | 306 | |
| Re B14,940,916 | 11/26/96 | Borel et al. | 315 | 306 | |
| 4,950,987 | 08/21/90 | Vranish et al. | 324 | 207.23 | |
| 4,952,446 | 08/18/90 | Lee et al. | 428 | 220 | |
| 4,954,865 | 09/04/90 | Rokos | 257 | 378 | |
| 4,957,882 | 09/18/90 | Shinomiya | 438 | 65 | |
| 4,965,415 | 10/23/90 | Young et al. | 200 | 83 N | |
| 4,966,663 | 10/30/90 | Mauger | 205 | 656 | |
| 4,994,735 | 02/19/91 | Leedy | 324 | 158 | |
| 5,008,619 | 04/16/91 | Keogh et al. | 324 | 207.17 | |
| 5,010,024 | 04/23/91 | Allen et al. | 438 | 659 | |
| 5,020,219 | 06/04/91 | Leedy | 29 | 846 | |
| 5,034,685 | 07/23/91 | Leedy | 324 | 158 F | |
| 5,070,026 | 12/03/91 | Greenwald et al. | 437 | 3 | |
| 5,071,510 | 12/10/91 | Findler et al. | 156 | 647 | |
| 5,098,865 | 03/24/92 | Machado et al. | 438 | 788 | |
| 5,103,557 | 04/14/92 | Leedy | 29 | 832 | |
| 5,110,373 | 05/05/92 | Mauger | 148 | 33.2 | |
| 5,111,278 | 05/05/92 | Eichelberger | 357 | 75 | |
| 5,116,777 | 05/26/92 | Chan et al. | 438 | 234 | |
| 5,130,894 | 07/14/92 | Miller | 361 | 393 | |
| 5,132,244 | 07/21/92 | Roy | 438 | 477 | |

EXAMINER

DATE CONSIDERED

EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not conformance and not considered. Include copy of this form with next communication to applicant.

| | | | | | |
|--|--|--|-----------------------------|----------------------------------|-------------------------------|
| FORM PTO-1449 | U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE | | | ATTY. DOCKET NO. ELM-2 Div. 6 | APPLICATION NO. 10/614,067 |
| INFORMATION DISCLOSURE STATEMENT BY APPLICANT | | | APPLICANT Glenn J. Leedy | CONFIRMATION NO. 8117 | |
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| 5,151,775 | 09/29/92 | Hadwin | 357 | 80 | |
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| 5,203,731 | 04/20/93 | Zimmerman | 445 | 24 | |
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| 5,262,351 | 11/16/93 | Bureau et al. | 437 | 183 | |
| 5,270,261 | 12/14/93 | Bertin et al. | 437 | 209 | |
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| 5,274,270 | 12/28/93 | Tuckerman | 257 | 758 | |
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| 5,284,796 | 02/08/94 | Nakanishi et al. | 437 | 183 | |
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| 5,324,687 | 06/28/94 | Wojnarowski | 437 | 225 | |
| 5,354,695 | 10/11/94 | Leedy | 438 | 411 | |
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| 5,527,645 | 06/18/96 | Pati et al. | 430 | 5 | |

EXAMINER

DATE CONSIDERED

EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not conformance and not considered. Include copy of this form with next communication to applicant.

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|---|--|-------------------|-----|----------------------------------|-------------------------------|
| FORM PTO-1449 INFORMATION DISCLOSURE STATEMENT BY APPLICANT | U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE | | | ATTY. DOCKET NO. ELM-2 Div. 6 | APPLICATION NO. 10/614,067 |
| | | | | APPLICANT Glenn J. Leedy | CONFIRMATION NO. 8117 |
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